

## Supporting Information

### Single Nucleation of Cl-doped FAPbBr<sub>3</sub> with Inhibited Ion Migration for Ambipolar Radiation Detection

Quanchao Zhang<sup>1</sup>, Xin Liu<sup>1\*</sup>, Xin Zhang<sup>1</sup>, Zijian Wang<sup>1</sup>, Baoqiang Zhang<sup>2</sup>, Yingying Hao<sup>1</sup>, Alain Dubois<sup>1,3</sup>, Wanqi Jie<sup>1</sup>, Yadong Xu<sup>1\*</sup>

<sup>1</sup>State Key Laboratory of Solidification Processing, MIIT Key Laboratory of Radiation Detection Materials and Devices, & School of Materials Science and Engineering, Northwestern Polytechnical University, Xi'an 710072, China

<sup>2</sup>Ametek Co., Ltd., Shaanxi Xixian New Area Qinhan New City Tian Gong 1 road 8-1, Xi'an 712000, China

<sup>3</sup>Laboratory of Physical Chemistry – Matter and Radiation, Sorbonne Université, CNRS-, 75005 Paris France

#### Corresponding Author

\* Tel: +86-29-88460445; Fax: 86-29-88495414

E-mail address: liuxin8@mail.nwpu.edu.cn (X. L.)

E-mail address: xyd220@nwpu.edu.cn (Y. X.).

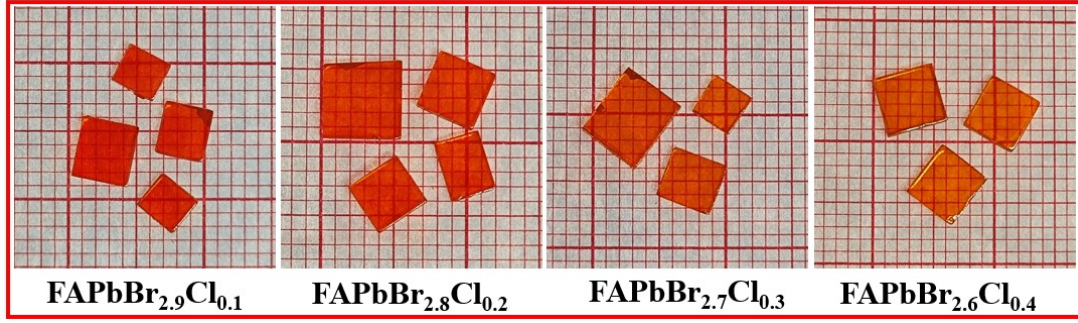
#### ORCID

Xin Liu: 0000-0002-0409-1718

Yadong Xu: 0000-0002-1017-9337

#### Notes

The authors declare no competing financial interest.



**Figure S1.** Photos of as-grown FAPbBr<sub>3</sub> SCs and FAPbBr<sub>3-x</sub>Cl<sub>x</sub> SCs with Cl/(Cl+Br) ratios varying from 3.3% to 13.3%.

The released expansion stress can be calculated by the formular<sup>[1]</sup>:

$$\sigma = 8\pi\mu r_{Cl}^3 \left( \frac{r_{Cl} - r_{Br}}{r_{Br}} \right)^2$$

where  $\mu = \frac{E}{2(1 + \delta)}$  is the shear modulus,  $E$  is the Young's modulus,  $\delta$  is the Poisson's ratio, and  $r_{Cl}$  and  $r_{Br}$  are the radii of Cl (1.67 Å) and Br (1.84 Å), respectively. Since  $E(\text{GPa}) = -232.25 + 267.06\tau$  where  $\tau$  is the tolerance factor<sup>[2]</sup>.

Table S3. Tolerance factor of the FAPbBr<sub>3-x</sub>Cl<sub>x</sub> SCs.

Cl	Br	Average radius of halide ion	Pb	FA <sup>+</sup>	$\tau$
0	3	0.184			1.0165
0.1	2.9	0.1834			1.0171
0.2	2.8	0.1829	0.12	0.253	1.0176
0.3	2.7	0.1823			1.0182
0.4	2.6	0.1817			1.0188

Notice: the calculation of the tolerance factor can be expressed as:

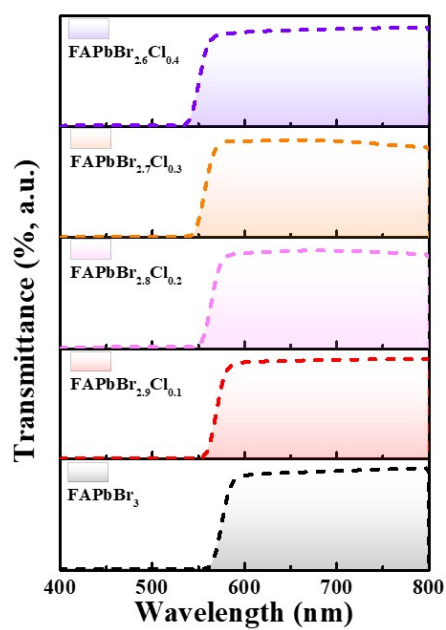
$$\tau = \frac{r_A + r_X}{\sqrt{2}(r_B + r_X)}$$

where  $r_A$ ,  $r_B$ ,  $r_X$  is the radius of A site cation (FA<sup>+</sup>), B site cation (Pb<sup>2+</sup>), and halide ion X<sup>-</sup>,

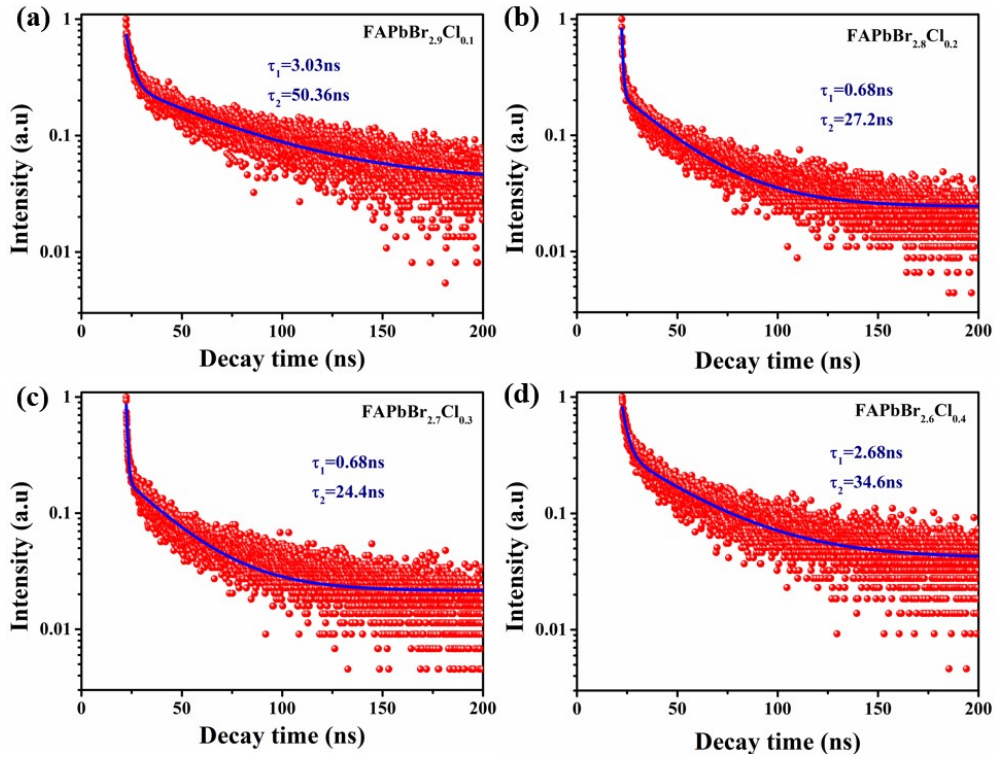
respectively.

**Table S2.** EDS component analysis of FAPbBr<sub>3-x</sub>Cl<sub>x</sub> SCs (The average of three points).

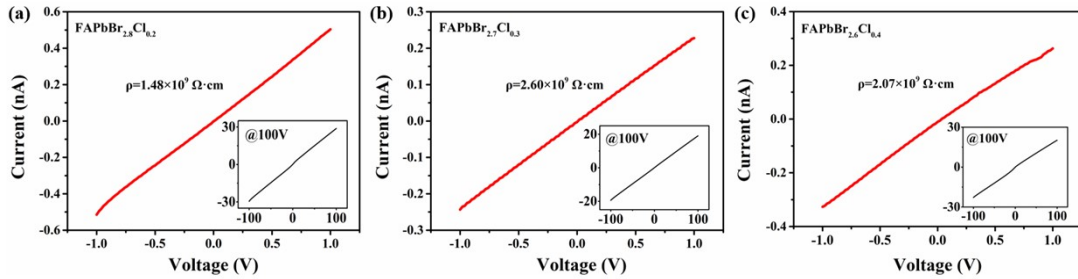
	C%	N%	Pb%	Br%	Cl%	Cl: X	Br: Cl
FAPbBr <sub>3</sub>	30.19	24.65	11.51	33.65	0	-	-
FAPbBr <sub>2.9</sub> Cl <sub>0.1</sub>	35.09	20.69	11.52	31.56	1.15	3.51	2.89: 0.11
FAPbBr <sub>2.8</sub> Cl <sub>0.2</sub>	26.20	28.16	11.71	31.91	2.01	5.93	2.82: 0.18
FAPbBr <sub>2.7</sub> Cl <sub>0.3</sub>	30.34	24.24	11.85	30.03	3.54	10.55	2.68: 0.32
FAPbBr <sub>2.6</sub> Cl <sub>0.4</sub>	34.40	23.22	10.97	27.26	4.15	13.20	2.60: 0.40



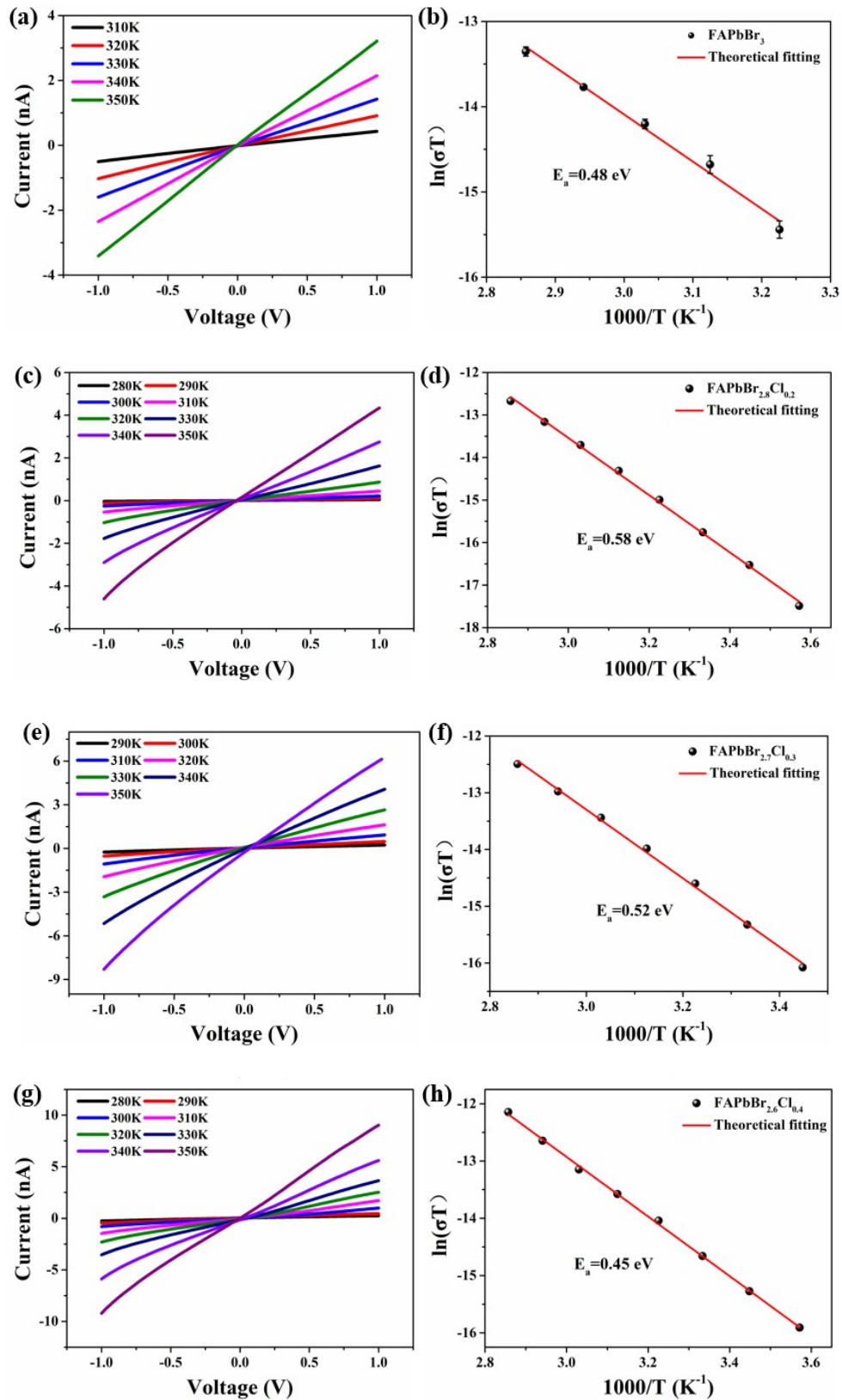
**Figure S2.** Ultraviolet transmittance spectrum of FAPbBr<sub>3-x</sub>Cl<sub>x</sub> SCs.



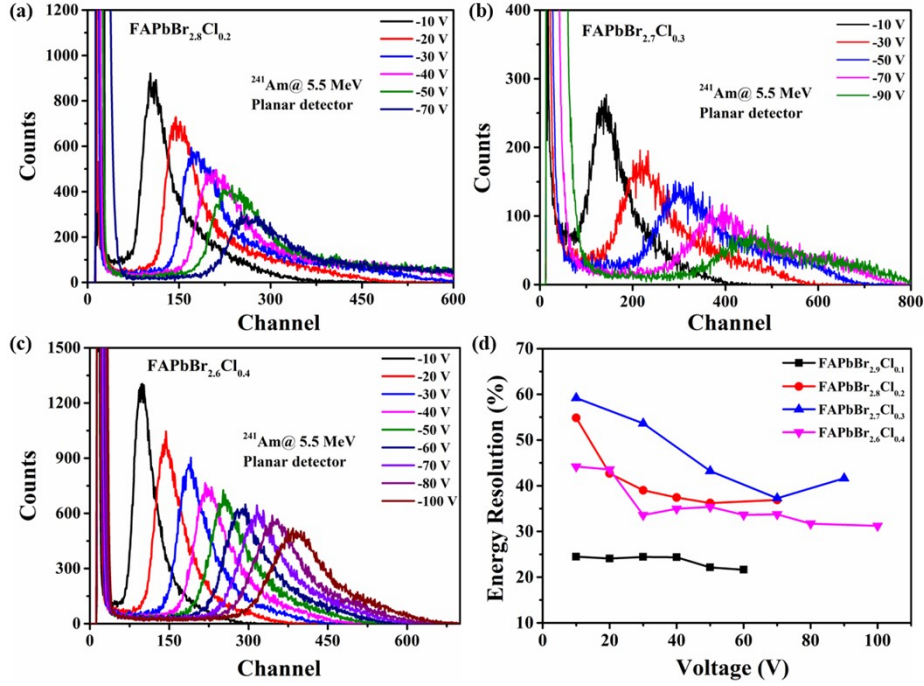
**Figure S3.** Charge recombination lifetime of FAPbBr<sub>3-x</sub>Cl<sub>x</sub> SCs by TRPL.



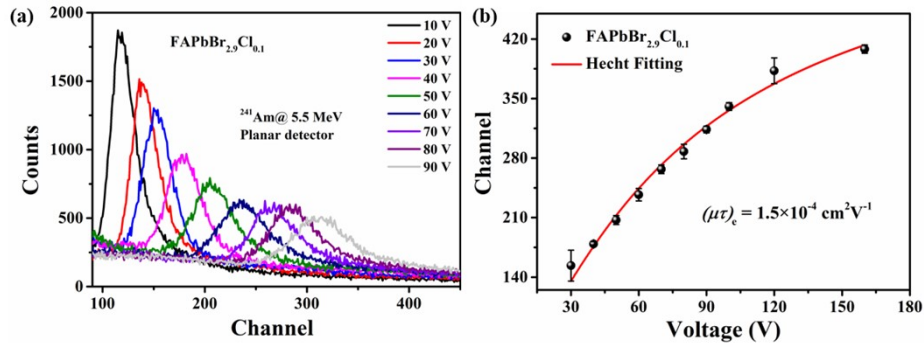
**Figure S4.** Dark  $I$ - $V$  curve of (a) Au/FAPbBr<sub>2.8</sub>Cl<sub>0.2</sub>/Au, (b) Au/FAPbBr<sub>2.7</sub>Cl<sub>0.3</sub>/Au, (c) Au/FAPbBr<sub>2.6</sub>Cl<sub>0.4</sub>/Au, devices at room temperature. The inset is the  $I$ - $V$  curve from -100 V to 100 V.



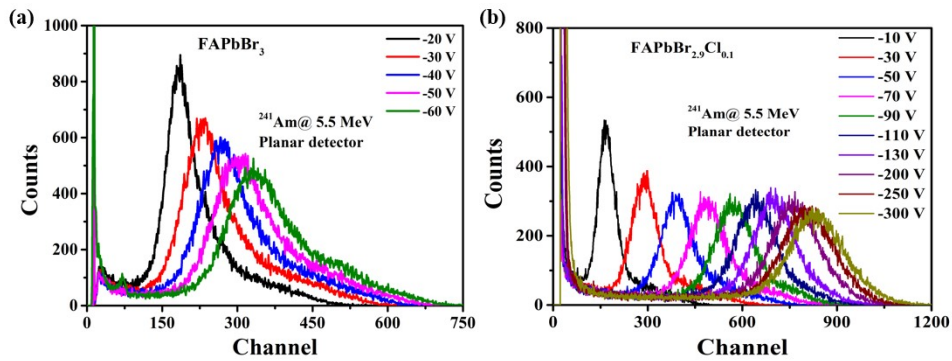
**Figure S5.** (a)(c)(e)(g) Dark  $I-V$  curve of Au/ FAPbBr<sub>3-x</sub>Cl<sub>x</sub>/Au devices at different temperatures. (b)(d)(f)(h) Temperature-dependent conductivity measurements of the corresponding FAPbBr<sub>3-x</sub>Cl<sub>x</sub> SCs.



**Figure S6.**  $^{241}\text{Am}$  5.5 MeV  $\alpha$ -particle energy spectra of (a) Au/FAPbBr<sub>2.8</sub>Cl<sub>0.2</sub>/Au, (b) Au/FAPbBr<sub>2.7</sub>Cl<sub>0.3</sub>/Au, (c) Au/FAPbBr<sub>2.6</sub>Cl<sub>0.4</sub>/Au devices under various bias voltages. (d) The comparison of energy resolution of FAPbBr<sub>3-x</sub>Cl<sub>x</sub> SCs under different voltages.



**Figure S7.** (a)  $^{241}\text{Am}$  5.5 MeV  $\alpha$ -particle energy spectra of Au/FAPbBr<sub>2.9</sub>Cl<sub>0.1</sub>/Au devices under various bias voltages. (b) Electron mobility-lifetime product by Hecht equation fitting.



**Figure S8.** Comparison of voltage resistance:  $^{241}\text{Am}$  5.5 MeV  $\alpha$ -particle energy spectra of (a) Au/FAPbBr<sub>3</sub>/Au, (b) Au/FAPbBr<sub>2.9</sub>Cl<sub>0.1</sub>/Au devices.

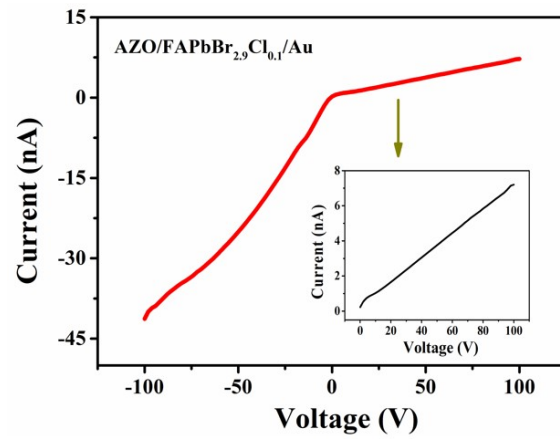


Figure S9. Typical dark  $I$ - $V$  characteristics of AZO/FAPbBr<sub>2.9</sub>Cl<sub>0.1</sub>/Au devices.

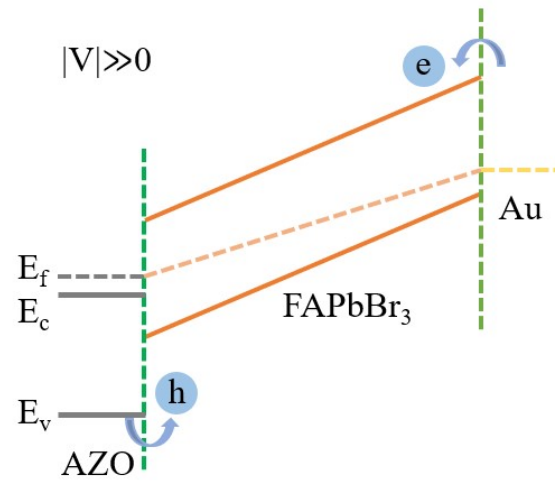


Figure S10 Band diagram of AZO/FAPbBr<sub>3</sub>/Au

**Table S3.** Material Properties and Device Performance of Commercialized Radiation Detectors

Materials	Growth method	Band gap (eV)	$\mu\tau$ product (cm <sup>2</sup> V <sup>-1</sup> )	Maximum Voltage on detector	Energy resolution (%)	Ref.
Ge	Czochralski	0.7	1	1000 V	0.14 (1 MeV/ $\gamma$ -ray)	[3]
CdZnTe	Bridgman	1.57	e: $1.2 \times 10^{-2}$ h: $9 \times 10^{-5}$	200 V	0.8 (662 keV/ $\gamma$ -ray)	[4, 5]
CdZnTe films	Close Spaced Sublimation	1.5	e: $2.562 \times 10^{-4}$	50 V	16.45 (5.48 MeV/ $\alpha$ particles)	[6]
CdTe	Bridgman	1.44	e: $3 \times 10^{-3}$ h: $2.6 \times 10^{-4}$	600V	12 (662 keV/ $\gamma$ -ray)	[7]
TlBr	traveling molten zone	2.68	e: $3 \times 10^{-5}$ e: $1.5 \times 10^{-6}$	200 V	3.3 (662 keV/ $\gamma$ -ray)	[8]
FAPbBr <sub>2.9</sub> Cl <sub>0.1</sub>	Inverse temperature crystallization	2.23	e: $2.1 \times 10^{-4}$ h: $1.5 \times 10^{-4}$	300 V	h: 21.3 e: 19.2 (5.48 MeV/ $\alpha$ particles)	This work



## Reference

- [1] H. Ye, Y. Liu, Y. Zhang, et al. Inner Strain Regulation in Perovskite Single Crystals through Fine-Tuned Halide Composition[J]. *Crystal Growth & Design*, 2021, 21(3): 1741-1750.
- [2] S. Sun, Y. Fang, G. Kieslich, et al. Mechanical properties of organic–inorganic halide perovskites,  $\text{CH}_3\text{NH}_3\text{PbX}_3$  (X = I, Br and Cl), by nanoindentation[J]. *Journal of Materials Chemistry A*, 2015, 3(36): 18450-18455.
- [3] I. Y. Lee, M. A. Deleplanque, K. Vetter. Developments in large gamma-ray detector arrays[J]. *Reports on Progress in Physics*, 2003, 66(7): 1095-1144.
- [4] F. Zhang, Z. He, C. E. Seifert. A Prototype Three-Dimensional Position Sensitive CdZnTe Detector Array[J]. *IEEE Transactions on Nuclear Science*, 2007, 54(4): 843-848.
- [5] F. Liu, R. Wu, J. Wei, et al. Recent Progress in Halide Perovskite Radiation Detectors for Gamma-Ray Spectroscopy[J]. *ACS Energy Letters*, 2022, 7(3): 1066-1085.
- [6] X. Wan, Y. Li, T. Tan, et al. Effects of annealing in Te<sub>2</sub> atmosphere on photoelectric properties and carrier transport properties of CdZnTe films[J]. *Materials Science in Semiconductor Processing*, 2023, 153(107158).
- [7] T. T. a. S. Watanabe. Recent Progress in CdTe and CdZnTe Detectors[J]. *IEEE TRANSACTIONS ON NUCLEAR SCIENCE*, 2001, 48(4).
- [8] K. Hitomi, Y. Kikuchi, T. Shoji, et al. Improvement of energy resolutions in TlBr detectors[J]. *Nuclear Instruments and Methods in Physics Research Section A: Accelerators, Spectrometers, Detectors and Associated Equipment*, 2009, 607(1): 112-115.